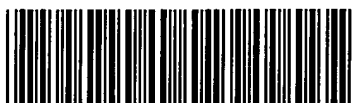


Search Notes

Application/Control No.

10/564,894

Examiner

Hai H. Huynh

Applicant(s)/Patent under
Reexamination

MORIYA ET AL.

Art Unit

3747

SEARCHED

Class	Subclass	Date	Examiner
123	299	8/23/2006	HHH
123	300	8/23/2006	HHH
123	305	8/23/2006	HHH
123	406.22	8/23/2006	HHH
123	406.26	8/23/2006	HHH
123	435	8/23/2006	HHH
123	90.15	8/23/2006	HHH
701	103-105	8/23/2006	HHH
701	111	8/23/2006	HHH
73	117.3	8/23/2006	HHH
73	118.1	8/23/2006	HHH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	8/23/2006	HHH